E UNITED STATES PATENT AND TRADEMARK OFFICE

Pater Application Serial No	
Filing Date	
Inventorship	Charles H. Dennison
Assignee	Micron Technology, Inc.
	2811
Examiner	Ori Nadav
	MI22-1577
Title	Field Effect Transistors and Integrated Circuitry

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. A copy of the cited art is attached hereto. No admission is made regarding whether the submitted reference is prior art.

This Supplemental Information Disclosure Statement is being filed before the mailing of a first office action after the filing of a request for continued examination. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated:

Mark S. Matkin

Reg. No. 32,268

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Patent Application Serial N	lo 09/730,335
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Group Art Unit	
Examiner	Ori Nadav
Attorney Docket No	MI22-1577
Customer No	
Title	Field Effect Transistors and Integrated Circuitry

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. Copies of the cited prior art references are attached. No admission is made regarding whether all the listed references are prior art.

Respectfully submitted,

Dated:

7-20-04

Mark S. Matkin Reg. No. 32,268

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	AK	03-	-192768	08/22/91	Japan (Masae)				Abstract	
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